

STD100NH03L

N-channel 30V - 0.005Ω - 60A - DPAK STripFET™ III Power MOSFET

General features

Туре	V _{DSSS}	R _{DS(on)}	I _D
STD100NH03L	30V	<0.0055Ω	60A ⁽¹⁾

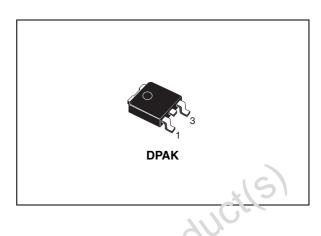
- 1. Value limited by wire bonding
- R_{DS(on)} * Qg industry's benchmark
- Conduction losses reduced
- Switching losses reduced
- Low threshold device

Description

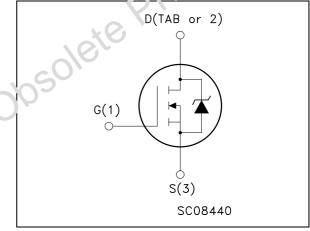
This device utilizes the latest advanced design rules of ST's proprietary STripFET™ technology. This is suitable fot the most demanding DC-DC converter application where high efficiency is to be achieved.

Applications

bsolete Productls



Internal schematic diagram



Order codes

Part number	Marking	Package	Packaging
STD100NH03LT4	D100NH03L	DPAK	Tape & reel

Contents

1	Electrical ratings
2	Electrical characteristics
3	Test circuit
4	Package mechanical data9
5	Packaging mechanical data 11
6	Revision history
	Electrical ratings 3 Electrical characteristics 4 2.1 Electrical characteristics (curves) 6 Test circuit 8 Package mechanical data 9 Packaging mechanical data 11 Revision history 14
0105	



1

Electrical ratings

Table 1. Absolute maximum ratings	Table 1.	Absolute	maximum	ratings
-----------------------------------	----------	----------	---------	---------

	Aboolato maximali ratingo		
Symbol	Parameter	Value	Unit
V _{DS}	Drain-source voltage ($V_{GS} = 0$)	30	V
V _{DGR}	Drain-gate voltage ($R_{GS} = 20K\Omega$)	30	V
V _{GS}	Gate-source voltage	± 20	V
I _D ⁽¹⁾	Drain current (continuous) at $T_C = 25^{\circ}C$	60	А
I _D ⁽¹⁾	Drain current (continuous) at T _C =100°C	60	А
I _{DM} ⁽²⁾	Drain current (pulsed)	240	А
P _{TOT}	Total dissipation at $T_{C} = 25^{\circ}C$	100	W
	Derating factor	0.66	W/°C
E _{AS} ⁽³⁾	Single pulse avalanche energy	700	mJ
T _{stg}	Storage temperature	-55 to 175	°C
TJ	Max. operating junction temperature	-55 10 175	C
1. Value I	limited by wire bonding.		
2. Pulse w	vidth limited by safe operating area		
3. Starting	g T _J = 25 °C, I _D = 30A, V _{DD} = 15V	ש`	
		101-	
Table 2.	Thermal data	01-	
Symbol	Parameter	Value	Unit

Table	2.	Thermal	data
-------	----	---------	------

Symbol	Parameter	Value	Unit
R _{thJC}	Thermal resistance junction-case Max	1.5	°C/W
R _{thJA}	Thermal resistance junction-ambient Max	100	°C/W
R _{thJ-PCB}	Thermal resistance junction-PCB Max	43	°C/W
Τ _Ι	Maximum lead temperature for soldering purpose	275	°C
soletef			

2 **Electrical characteristics**

(T_{CASE} = 25°C unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	I _D = 25mA, V _{GS} = 0	30			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V _{DS} = 20 V _{DS} = 20, T _C = 125°C			1 10	μA μA
I _{GSS}	Gate body leakage current (V _{DS} = 0)	$V_{GS} = \pm 20V$			±100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1	1.8	2.5	v
R _{DS(on)}	Static drain-source on resistance	$V_{GS} = 10V, I_D = 30A$ $V_{GS} = 5V, I_D = 30A$		0.005 0.0060	0.0055 0.0105	Ω Ω
Table 4.	Dynamic			901	9-	
	B	-		-		

Table 3. On /off states

Table 4. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
$g_{fs}^{(1)}$	Forward transconductance	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 30 \text{ A}$		40		S
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} = 15V, f = 1 MHz, V _{GS} = 0		4100 680 70		pF pF pF
R _G	Gate input resistance	f = 1MHz gate DC bias = 0 test signal level = 20mV Open drain		1.3		Ω
Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	V _{DD} = 10V, I _D = 60A V _{GS} = 10V		57 11.8 7.3	77	nC nC nC
Q _{oss} ⁽²⁾	Output charge	V _{DS} = 16V, V _{GS} = 0V		27		nC
Q _{gls} ⁽³⁾	Third-quadrant gate charge	V _{DS} < 0V, V _{GS} = 10V		55		nC
2. $Q_{OSS} = C_0$	bulse duration=300 μ s, duty cycle $c_{DSS}^{*}\Delta V_{in}$, $C_{OSS} = C_{gd} + C_{dS}$. See <i>C</i> arge for synchronous operation		•			



105h

		e mile mile e					
ſ	Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
	t _{d(on)} t _r t _{d(off)} t _f	Turn-on delay time Rise time Turn-off delay time Fall time	$V_{DD} = 15V, I_D = 30A,$ $R_G = 4.7\Omega, V_{GS} = 10V$ Figure 13 on page 8		16 95 48 23	47	ns ns ns ns

Table 5. Switching times

Table 6. Source drain diode

57

GC94800

2.1 Electrical characteristics (curves)

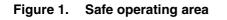


Figure 2. Thermal impedance

0.0

0.02

0.01

10⁻²

10⁻³

Transfer characteristics

SINGLE PULSE

10⁻⁴

 $Z_{th} = k R_{thJ-c}$

 $10^{-1} t_{P}(s)$

57

 $\delta = t_p / \tau$

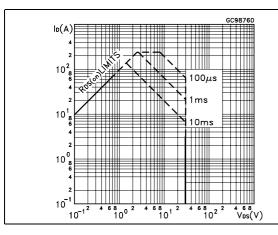
К

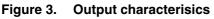
10

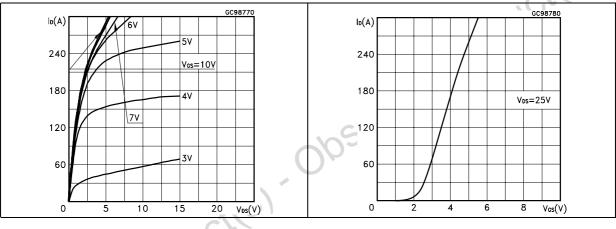
10

Figure 4.

10⁻⁵

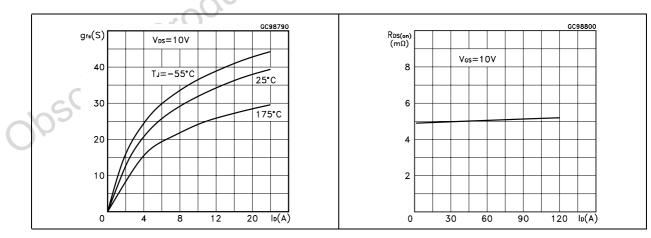












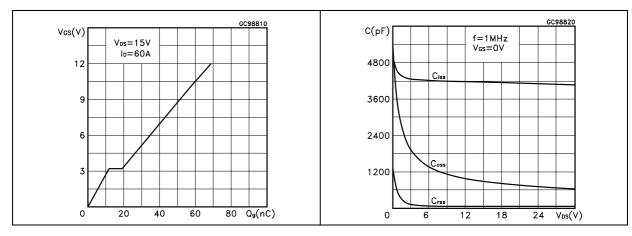


Figure 7. Gate charge vs gate-source voltage Figure 8. Capacitance variations



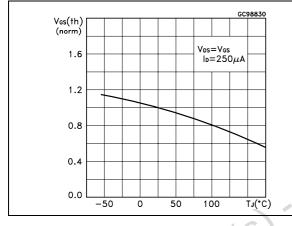
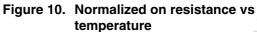


Figure 11. Source-drain diode forward characteristics



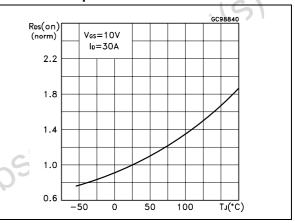
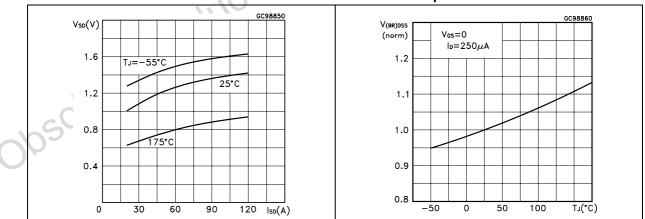


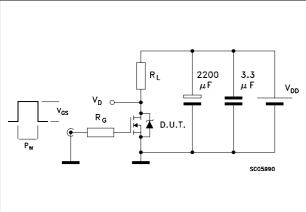
Figure 12. Normalized breakdown voltage vs temperature



57

3 Test circuit

Figure 13. Switching times test circuit for resistive load



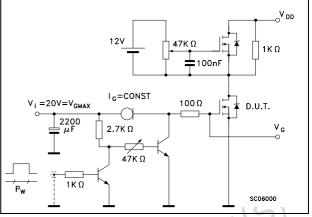
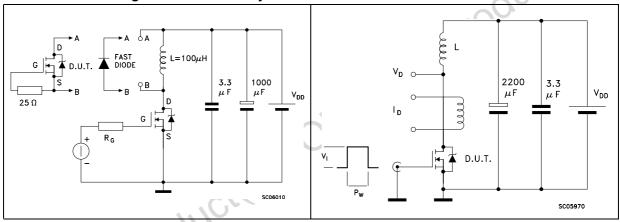


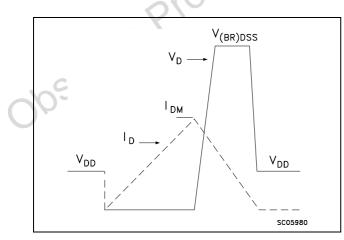
Figure 14. Gate charge test circuit

Figure 15. Test circuit for inductive load switching and diode recovery times

Figure 16. Unclamped Inductive load test circuit







4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect. The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com

obsolete Product(s). Obsolete Product(s)

57

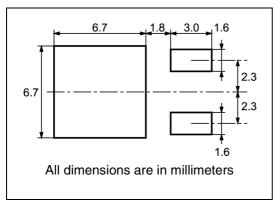
	DIM.		mm.			inch	
	DIM.	MIN.	ТҮР	MAX.	MIN.	TYP.	MAX.
	Α	2.2		2.4	0.086		0.094
-	A1	0.9		1.1	0.035		0.043
	A2	0.03		0.23	0.001		0.009
	В	0.64		0.9	0.025		0.035
	b4	5.2		5.4	0.204		0.212
	С	0.45		0.6	0.017		0.023
	C2	0.48		0.6	0.019		0.023
	D	6		6.2	0.236		0.244
	D1		5.1			0.200	
	E	6.4		6.6	0.252		0.260
	E1		4.7			0.185	
	е		2.28			0.090	
	e1	4.4		4.6	0.173		0.181
	Н	9.35		10.1	0.368		0.397
	L	1			0.039		
	(L1)		2.8			0.110	
	L2		0.8			0.031	
	L4	0.6		1	0.023		0.039
	R V2	0°	0.2	8°	0°	0.008	8°
		Г Н					
016		_		(2x)	R	Ŧ	



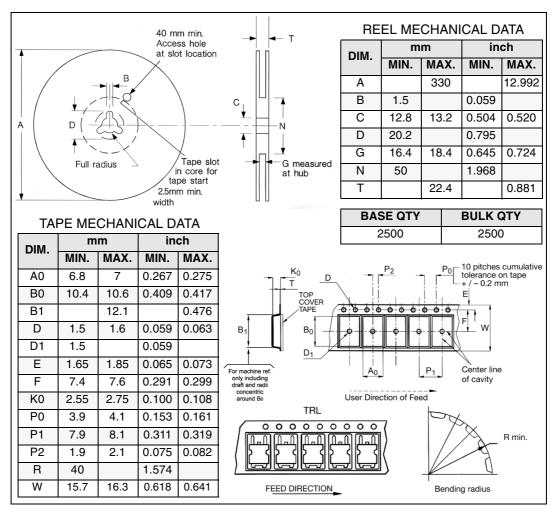
5

Packaging mechanical data





TAPE AND REEL SHIPMENT



Appendix A Buck converter - power losses estimation

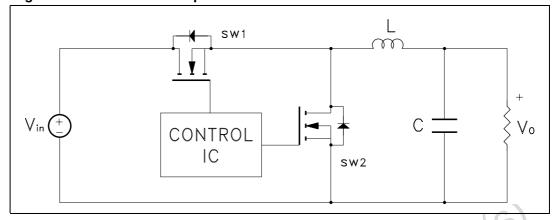


Figure 18. Buck converter: power losses estimation

The power losses associated with the FETs in a synchronous buck converter can be estimated using the equations shown in the table below. The formulas give a good approximation, for the sake of performance comparison, of how different pairs of devices affect the converter efficiency. However a very important parameter, the working temperature, is not considered. The real device behavior is really dependent on how the heat generated inside the devices is removed to allow for a safer working junction temperature.

- The low side (SW2) device requires:
- Very low R_{DS(on)} to reduce conduction losses
- Small QgIs to reduce the gate charge losses
- Small Coss to reduce losses due to output capacitance
- Small Qrr to reduce losses on SW1 during its turn-on
- The Cgd/Cgs ratio lower than Vth/Vgg ratio especially with low drain to source
- voltage to avoid the cross conduction phenomenon;
- The high side (SW1) device requires:
- Small Rg and Ls to allow higher gate current peak and to limit the voltage feedback on the gate
- Small Qg to have a faster commutation and to reduce gate charge losses
- Low R_{DS(on)} to reduce the conduction losses.



ipsole



		High side switching (SW1)	Low side switch (SW2)
Pconduction		$R_{DS(on)SW1} * I_L^2 * \delta$	$R_{DS(on)SW2} * I_L^2 * (1 - \delta)$
Pswitching		$V_{in} * (Q_{gsth(SW1)} + Q_{gd(SW1)}) * f * \frac{I_L}{I_g}$	Zero Voltage Switching
Pdiode	Recovery	Not applicable	$V_{in} * Q_{rr(SW2)} * f$
	Conductio n	Not applicable	$V_{f(SW2)} * I_L * t_{deadtime} * f$
Pgate(Q _G)		$Q_{g(SW1)} * V_{gg} * f$	$Q_{gls(SW2)} * V_{gg} * f$
P _{Qoss}		$\frac{V_{in} * Q_{oss(SW1)} * f}{2}$	$\frac{V_{in} * Q_{oss(SW2)} * f}{2}$

Table 7. Power losses calculation

Paramiters meaning Table 8.

	Image: Coss of the second s				
	Parameter	Meaning			
	d	Duty-cycle			
	Q _{gsth}	Post threshold gate charge			
	Q _{gls}	Third quadrant gate charge			
	Pconduction	On state losses			
	Pswitching	On-off transition losses			
	Pdiode	Conduction and reverse recovery diode losses			
	Pgate	Gate drive losses			
SO.	P _{Qoss}	Output capacitance losses			
005					



57

6 Revision history

Table 9.	Revision	history
----------	----------	---------

Date	Revision	Changes
09-Sep-2004	3	Complete document
08-Aug-2006	4	New template, updated SOA

obsolete Product(s). Obsolete Product(s)

Please Read Carefully:

Information in this document is provided solely in connection with ST products. STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, modifications or improvements, to this document, and the products and services described herein at any time, without notice.

All ST products are sold pursuant to ST's terms and conditions of sale.

Purchasers are solely responsible for the choice, selection and use of the ST products and services described herein, and ST assumes no liability whatsoever relating to the choice, selection or use of the ST products and services described herein.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted under this document. If any part of this document refers to any third party products or services it shall not be deemed a license grant by ST for the use of such third party products or services, or any intellectual property contained therein or considered as a warranty covering the use in any manner whatsoever of such third party products or services or any intellectual property contained therein.

UNLESS OTHERWISE SET FORTH IN ST'S TERMS AND CONDITIONS OF SALE ST DISCLAIMS ANY EXPRESS OR IMPLIED WARRANTY WITH RESPECT TO THE USE AND/OR SALE OF ST PRODUCTS INCLUDING WITHOUT LIMITATION IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE (AND THEIR EQUIVALENTS UNDER THE LAWS OF ANY JURISDICTION), OR INFRINGEMENT OF ANY PATENT, COPYRIGHT OR OTHER INTELLECTUAL PROPERTY RIGHT.

UNLESS EXPRESSLY APPROVED IN WRITING BY AN AUTHORIZED ST REPRESENTATIVE, ST PRODUCTS ARE NOT RECOMMENDED, AUTHORIZED OR WARRANTED FOR USE IN MILITARY, AIR CRAFT, SPACE, LIFE SAVING, OR LIFE SUSTAINING APPLICATIONS, NOR IN PRODUCTS OR SYSTEMS WHERE FAILURE OR MALFUNCTION MAY RESULT IN PERSONAL INJURY, DEATH, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE. ST PRODUCTS WHICH ARE NOT SPECIFIED AS "AUTOMOTIVE GRADE" MAY ONLY BE USED IN AUTOMOTIVE APPLICATIONS AT USER'S OWN RISK.

Resale of ST products with provisions different from the statements and/or technical features set forth in this document shall immediately void any warranty granted by ST for the ST product or service described herein and shall not create or extend in any manner whatsoever, any liability of ST.

ST and the ST logo are trademarks or registered trademarks of ST in various countries.

Information in this document supersedes and replaces all information previously supplied.

The ST logo is a registered trademark of STMicroelectronics. All other names are the property of their respective owners.

© 2006 STMicroelectronics - All rights reserved

STMicroelectronics group of companies

Australia - Belgium - Brazil - Canada - China - Czech Republic - Finland - France - Germany - Hong Kong - India - Israel - Italy - Japan -Malaysia - Malta - Morocco - Singapore - Spain - Sweden - Switzerland - United Kingdom - United States of America

www.st.com

